

60V N-Channel Enhancement Mode MOSFET

Description

The AP85N06D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 60V$ $I_D = 85A$

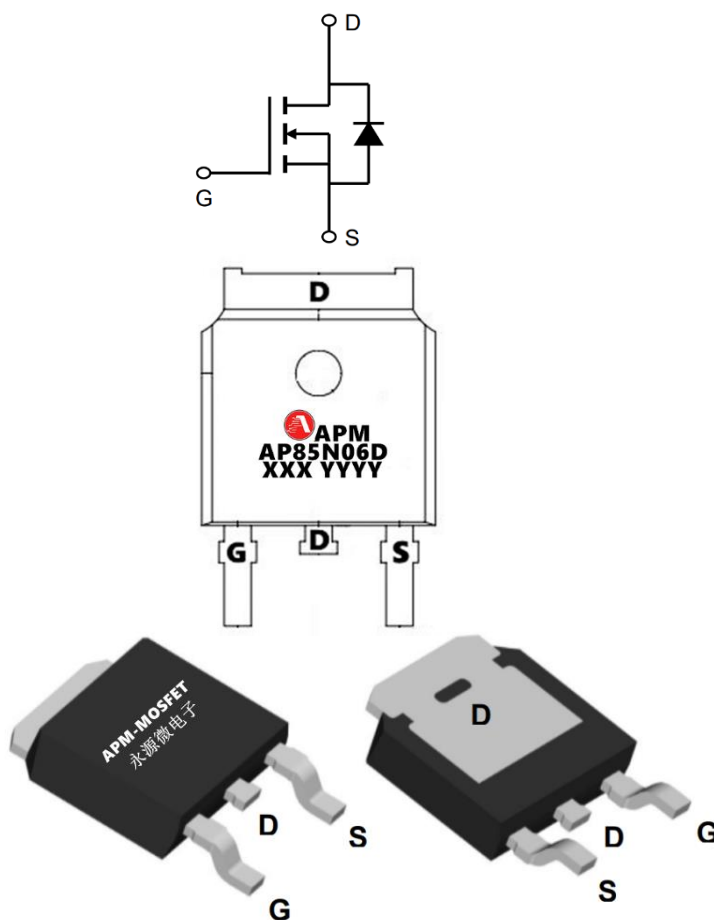
$R_{DS(ON)} < 8.5m\Omega$ @ $V_{GS}=10V$ (Type: 7.0m Ω)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP85N06D	TO-252-3L	AP85N06D XXX YYYY	1000

Absolute Maximum Ratings@ $T_J=25^{\circ}C$ (unless otherwise specified)

Symbol	Parameter	Value	Unit
V_{DS}	Drain source voltage	60	V
V_{GS}	Gate source voltage	± 20	V
$I_D@T_C=25^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	85	A
$I_D@T_C=100^{\circ}C$	Continuous Drain Current, $V_{GS} @ 10V^1$	21	A
IDM	Pulsed drain current ²⁾	415	A
IAS	Diode forward current	35	A
$P_D@T_C=25^{\circ}C$	Power dissipation	70	W
EAS	Single pulsed avalanche energy ³⁾	121	mJ
T_{stg}, T_J	Operation and storage temperature	-55 to 150	$^{\circ}C$
$R_{\theta JC}$	Thermal resistance, junction-case	2.14	$^{\circ}C/W$
$R_{\theta JA}$	Thermal resistance, junction-ambient ⁴⁾	62.5	$^{\circ}C/W$



60V N-Channel Enhancement Mode MOSFET
Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	60	65	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =60V, V _{GS} = 0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.2	1.8	2.5	V
RDS(on)	Static Drain-Source on-Resistance note3	V _{GS} =10V, I _D =30A	-	7.0	8.5	mΩ
		V _{GS} =4.5V, I _D =20A	-	8.5	10	
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	-	4605	-	pF
C _{oss}	Output Capacitance		-	215	-	pF
C _{rss}	Reverse Transfer Capacitance		-	191	-	pF
Q _g	Total Gate Charge	V _{DS} =30V, I _D =30A, V _{GS} =10V	-	77	-	nC
Q _{gs}	Gate-Source Charge		-	9	-	nC
Q _{gd}	Gate-Drain("Miller") Charge		-	23	-	nC
td(on)	Turn-on Delay Time	V _{DS} =30V, I _D =30A, R _G =1.8Ω, V _{GS} =10V	-	7.1	-	ns
t _r	Turn-on Rise Time		-	5.3	-	ns
td(off)	Turn-off Delay Time		-	27.2	-	ns
t _f	Turn-off Fall Time		-	6.2	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	58	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	232	A
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	I _F =30A, dI/dt=100A/μs	-	29	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	45	-	nC

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2、The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、The test cond \cong 300us duty cycle \cong 2%, duty cycle ition is $T_J=25^{\circ}\text{C}$, $V_{DD}=48V$, $V_G=10V$, $R_G=25\Omega$, $L=0.1mH$, $I_{AS}=35A$
- 4、The power dissipation is limited by 175°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

60V N-Channel Enhancement Mode MOSFET

Typical Characteristics

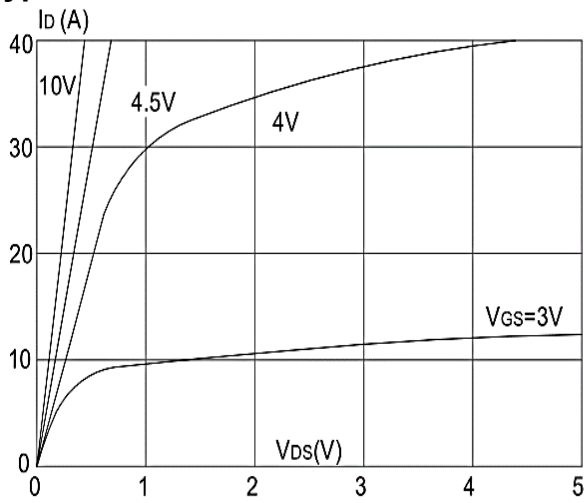


Figure1: Output Characteristics

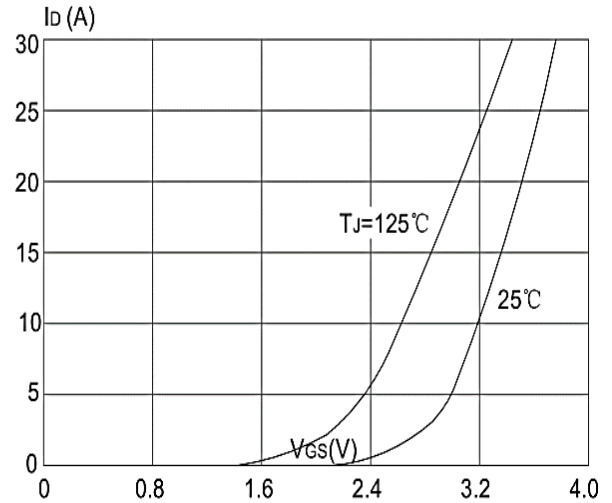


Figure 2: Typical Transfer Characteristics

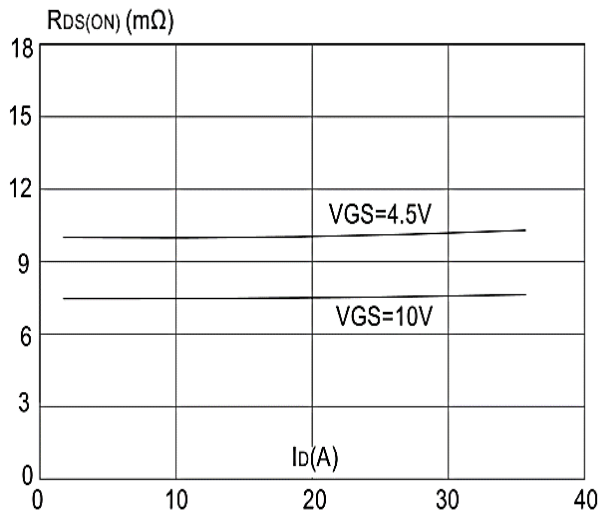


Figure 3: On-resistance vs. Drain Current

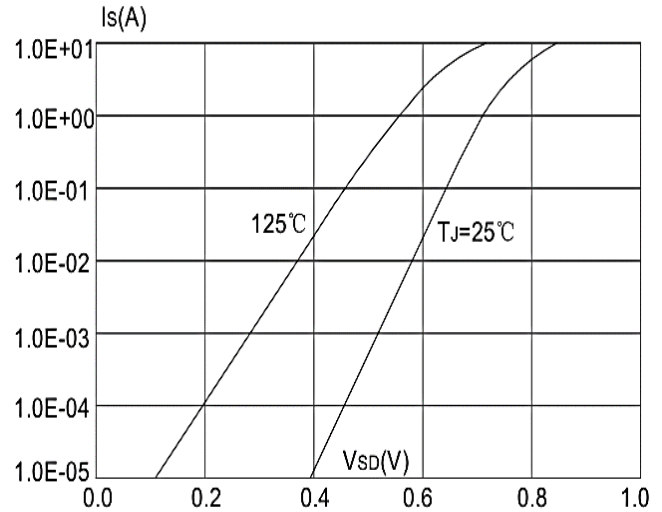


Figure 4: Body Diode Characteristics

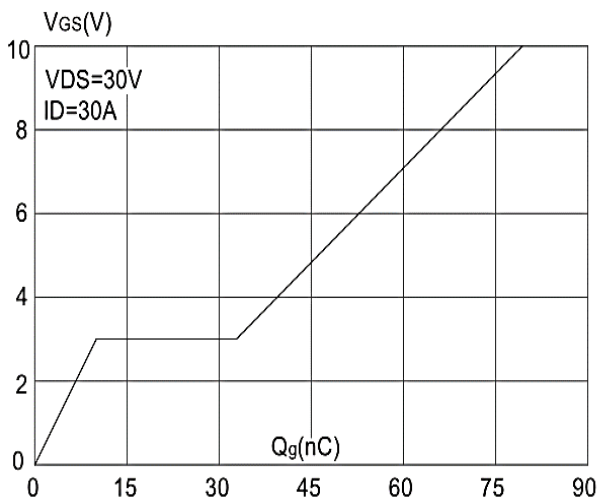


Figure 5: Gate Charge Characteristics

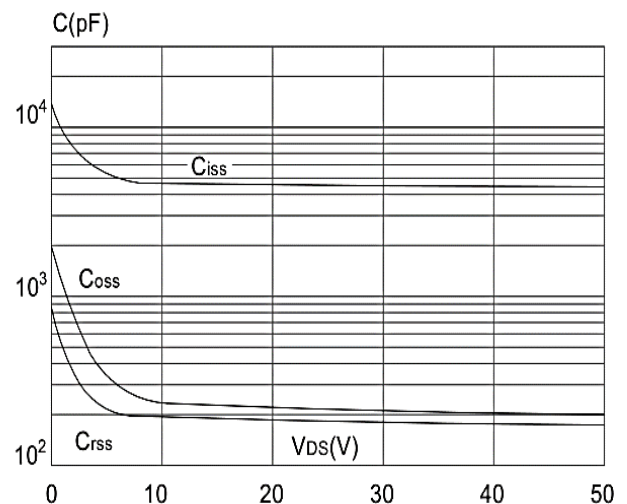


Figure 6: Capacitance Characteristics

60V N-Channel Enhancement Mode MOSFET

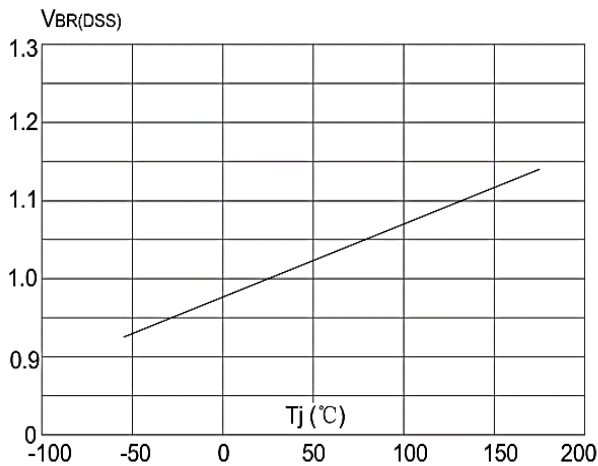


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

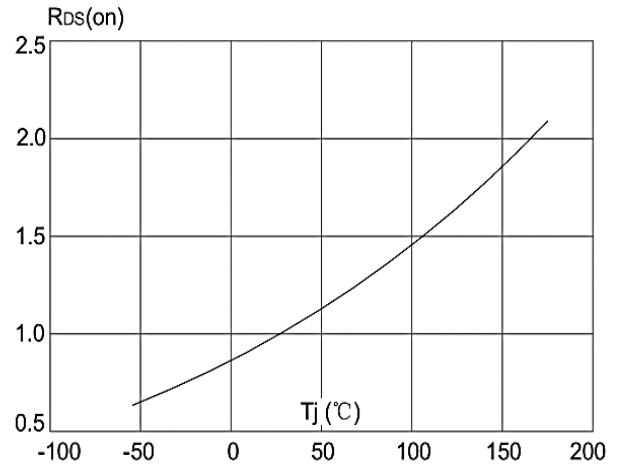


Figure 8: Normalized on Resistance vs. Junction Temperature

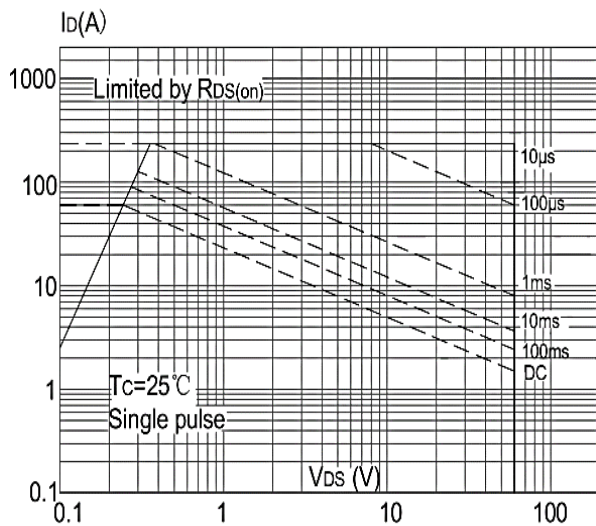


Figure 9: Maximum Safe Operating Area

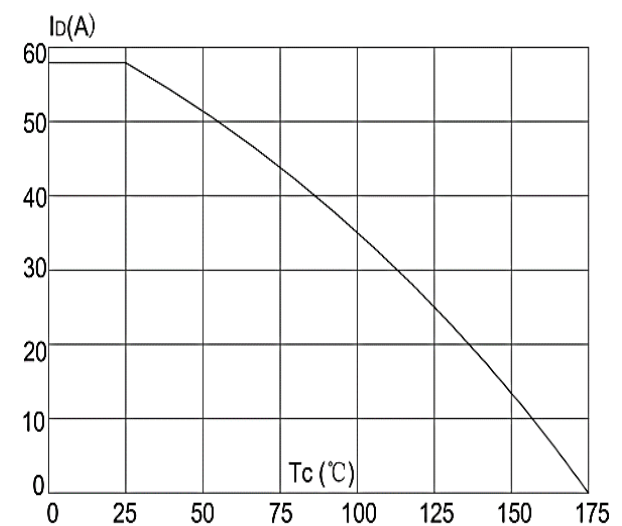


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

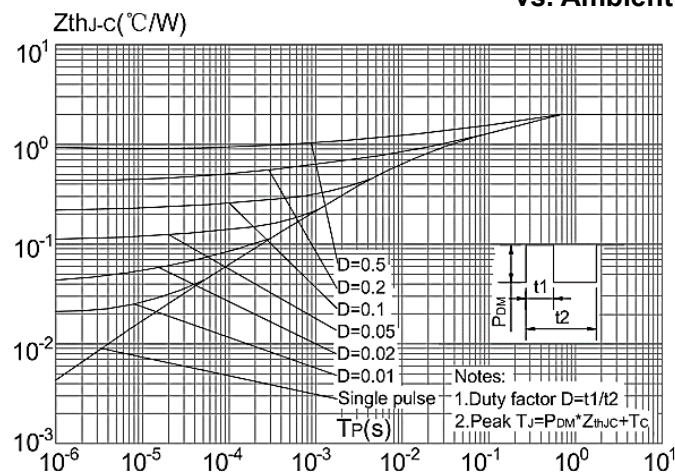
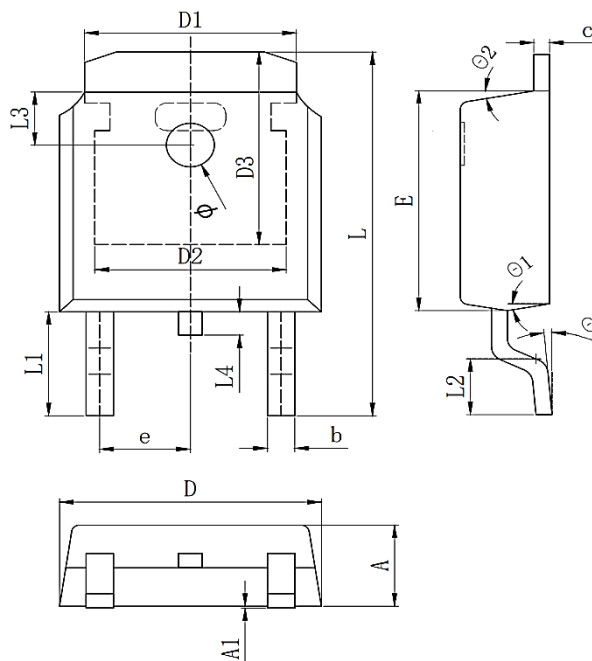


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien

Package Mechanical Data-TO-252-3L



Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
φ	1.1	1.2	1.3
θ	0°		10°
θ1	5°		10°
θ2	5°		10°

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Edition	Date	Change
REV1.0	2022/7/15	Initial release

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